Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 30-5000-(4015) Div. 2

PRIORITY SERIAL NO. 09/449,025

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A	AG _		ectromigration F 45-2750.	Properties of C	Copper-Zirconium alloy Interconne	cts, Y. Igarashi et al.,	J. Vac. Sci.	Technol. B 16	6(5), Sept/Oct	. 1998, р.
A	AH _	Di	irectional and Pi	referential Spu	attering-Based Physical Vapor Dep	osition, S.M. Rossnage	1, 1995 Elsev	ier Science S.	A., p. 1-12.	
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A	AL		ternational Criti nerica, Volumes		Numerical Data, Physics, Chemistr 6 pages.	y and Technology, <i>Nat</i>	ional Researc	ch Council of	the United Si	tates of
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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF ART CITED BY APPLICANT

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ATTY. DOCKET NO. 30-5000-(4015)-Div2

SERIAL NO. 09/784,233

APPLICANT Shozo Nagano et al.

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1	AA	6,113,761	09/05/00	Kardokus et al.		204	298.13		
R	AB	6,093,966	07/25/00	Venkatraman et al.	• "	257	751		
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a	AA	3,666,666	05/30/72	Haertling		252	62.9		
	AB	3,923,675	12/02/75	Mazdiyasni et al.		252	62.9		
\	AC	5,086,617	11/19/91	Tanemoto et al.		501	134		
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	AR	Foster, Composition	on and Structure	of Sputtered Films of Ferroelectric N	liobates, 8 THE JOURNA	AL OF VACUUM	A SCIENCE A	IND TECHNOLOGY,	No. 1,
1		pp. 251-2	55 (1971).	<u> </u>	,				
12	AS	Haertling, Hot-Pre	ssed Ferroelectri	c Lead Zirconate Titanate Ceramics f	or Electro-Optical Appl	lications, 49	CERAMIC BU	LLETIN, No. 6,	
		pp. 584-5	67 (1970).						
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 30-5000-(4015)-Div2

SERIAL NO. 09/784,233

LIST OF ART CITED BY APPLICANT

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APPLICANT Shozo Nagano et al.

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	(2	AA	3,963,934	06/15/76	Ormrod	250	499		
		AB	4,132,614	01/02/79	Cuomo et al.	204	192 EC		
		AC	4,149,907	04/17/79	Wronski et al.	148	1.5		
		AD	4,159,909	07/03/79	Wilson	75	170		
		AE	4,198,283	04/15/80	Class et al.	204	298		
		· AF	4,209,375	06/24/80	Gates et al.	204	192 R		
		AG	4,395,979	05/31/83	Pierce et al.	204	298		
		АН	4,545,882	10/08/85	McKelvey	204	192 R		
		Al	4,629,859	12/16/96	Reddy	219	121 LM		
		Ą	4,814,053	03/21/89	Shimokawato	204	192.15		
	1	AK	5,171,411	12/15/92	Hillendahl et al.	204	192.12		
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	63	AL	EP 0 882 813 A1	09.12.98	Europe (Takahashi)				-
		AM	61084389 A2 *	28.04.86	Japan (Takewaki) - Abstract only				
		AN	61113740 A2 3	31.05.86	Japan (Tanaka) - Abstract only				
	1	AO	62127438 ^E	09.06.87	Japan (Tatsuta) - Abstract only				
	13	AP	63033174 Q .	12.02.88	Japan (Kezuka) - Abstract only				
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		AS	Lucke et al., Physic	cal Mutalurgy F	Principles, 5 ACTA MET. 298 (1957).				
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	1		Diagram at al. Tota	I sputtering yie	old of Ag/Cu alloys for low energy argon ions, Nucl. Ins	TR. AND METH.	IN PHYS. RES.	108 B, pp. 29	0-299
	1	AT	Pietson et al., 70ta						
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in

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	AC	5,848,389	12/08/98	Levine et al.		204	192.1		
	AD	6,010,583	01/04/00	Annavarapu et al.		148	513		
	AE	6,028,003	02/22/00	Frisa et al.		438	653		
	AF	6,039,855	03/21/00	Wollenberg		204	298.12		
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	AJ	6,117,281	09/12/00	Novbakhtian		204	192.16		
	AK	6,121,685	09/19/00	Gardner		257	762	<u>.</u>	
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SERIAL NO. 09/784,233 ATTY. DOCKET NO. Form PTO-1449 U.S. DEPARTMENT OF COMMERCE 30-5000-(4015)-Div2 PATENT AND TRADEMARK OFFICE ST OF ART CITED BY APPLICANT **APPLICANT** (Use several then if necessary) Shozo Nagano et al. FILING DATE February 14, 2001 GROUP U,S PATENT DOCUMENTS **肥 12** 2001 To Class Subclass Filing Date If Appropriate Document Number Name 4,676,827 AA ΑB 4,986,856 5,077,005 12-31-91 AD 6,117,781 9-12-00 Lukanc et al. ΑE 6,117,782 9-12-00 Lukanc et al. Avanzino et al. ΑF 6,121,150 6.197.433 3-6-01 Hatano AG ΑH ΑI AJ ΑK FOREIGN PATENT DOCUMENTS Country Class Subclass Translation Yes No ΑМ AN ΑO AΡ OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) -ACCANA DI PORTO DI P AR AS DATE CONSIDERED **EXAMINER** S. Ip *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.